

General information

Organisation name : *Tescan Analytics*
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Targetted topics: (maximum 3)





- **HORIZON-CL4-2022-RESILIENCE-01-19:** Advanced materials modelling and characterisation (RIA)
- **HORIZON-CL4-2022-DIGITAL-EMERGING-02-19 :** 2D materials-based devices and systems for biomedical applications
- **HORIZON-CL4-2022-TWIN-TRANSITION-01-02 :** Products with complex functional surfaces (Made in Europe Partnership) (RIA)

Competencies

1. Materials analysis, surfaces and interfaces :

- a. Dimensions measurement, morphology, micro and nanostructure, interfaces analysis
- b. Composition analysis, chemical properties
- c. Defects & contaminations, anomaly investigation

2. Our values :

- a. **Reactivity**, 15 business days for standard services 
- b. **Multi-technique**, single entry point to state-of-the-art characterization 
- c. **Confidentiality** systematically with and without NDAs and/or collaboration contract 
- d. **Support**, with more than 20 years of experience in the field 

TOF-SIMS¹/GCIB¹

Molecular analysis, mapping and profiling of the first mono-layer to several micrometers

¹Time-Of-Flight Secondary Ion Mass Spectrometry
¹Ar Gas Cluster Ion Beam

AFM²

Nanometer-scale 3D topography, surface mechanical, adhesive and electrical properties

²Atomic Force Microscopy

PO3D³

Contactless 3D topography

³Optical 3D Profilometry

XPS⁴

Elementary and semi-quantitative chemical analysis, concentration mapping and profiling up to one micrometer

⁴X-Ray Photoelectron Spectroscopy

TEM (EDX/EELS)⁵

Atomic-scale morphological, structural and chemical analysis

⁵Transmission Electron Microscope (Energy-Dispersive X-Ray Spectroscopy/Electron Energy Loss Spectroscopy)

Sample Preparation

Cryo ultra Microtomy FIB⁶

⁶Focused Ion Beam

Nano-Engineering

Focused Ion Beam (Ga FIB, Xe Plasma FIB⁶)

SEM (EDX/EBSD)⁷

Morphology, microstructure and elemental chemistry

⁷Scanning Electron Microscopes (Energy-Dispersive X-Ray Spectroscopy / Electron BackScattered Diffraction)

